

Fig. 2. Comparison between the $ScRhSi_2$ and the TiNiSi types (*Pnma* setting).

arrangement resembles that found in the TiNiSi type (Shoemaker & Shoemaker, 1965) (Fig. 2b), of which ScNiSi and ScCoSi (Kotur & Bodak, 1977) constitute a subtype. The geometrical form of the coordination polyhedra for the Si atoms is similar in both structures but only in ScRhSi₂ do the polyhedra contain Si atoms. The geometrical environment of Rh in ScRhSi₂ is similar to that of Ni in TiNiSi.

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Trirhodium Scandium Heptasilicide and Triiridium Scandium Heptasilicide with a New Rhombohedral Structure Type

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Abstract. ScRh₃Si₇: a = 7.5056 (6), c = 19.691 (4) Å, $D_x = 5.706$ Mg m⁻³, μ (Mo $K\alpha$) = 9.6 mm⁻¹, F(000) =1524; ScIr₃Si₇: a = 7.5010 (2), c = 19.909 (1) Å, $D_x =$ 8.403 Mg m⁻³, μ (Mo $K\alpha$) = 67 mm⁻¹, F(000) = 2100. ScRh₃Si₇ and ScIr₃Si₇ crystallize with a new rhombohedral structure type in space group $R\bar{3}c$, Z = 6. For ScRh₃Si₇ (ScIr₃Si₇) the final R = 0.037 (0.072) for 272 (250) reflections. The Rh and Sc arrangement found in ScRh₃Si₇ is similar to that found in the PdF₃-type structure. Sc (Pd) are at the centres of octahedra formed by a hexagonal close-packed array of Rh (F) atoms. The crystal structures of ScRh₃Si₇ and ScIr₃Si₇ are stabilized by strong Rh-Si and Ir-Si interactions with each Si surrounded by three Rh or Ir atoms.

Introduction. Of the nine ternary phases found in the Si-rich part of the Sc–Rh–Si phase diagram (Braun, Burri & Rinderer, 1979), two have been analysed structurally. $Sc_5Rh_4Si_{10}$ crystallizes with a new tetragonal structure type (Braun, Yvon & Braun, 1980) and orthorhombic ScRhSi₂ is an ordered version of the YZn₃ type (Chabot, Braun, Yvon & Parthé, 1981). The phase on which we report here was given the composition ScRh₃Si₆ by Braun, Burri & Rinderer

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(1979). However, the crystal structure analysis revealed the true composition to be $ScRh_3Si_7$. $ScRh_3Si_7$ does not show any superconductivity (H. F. Braun, personal communication).

Sc-Rh-Si and Sc-Ir-Si alloys were prepared from elements of high purity (sublimed Sc 99.95% and 99.9% for Rh and Ir) by arc-melting techniques under an argon atmosphere.

Single crystals were isolated from crushed melts with starting composition 1:3:6. The true composition of the phase was revealed later to be 1:3:7. The mean diameter for the single crystal of $ScRh_3Si_7$ was 80 μ m and for $ScIr_3Si_7$ 60 μ m. Cells are triple hexagonal and their parameters were obtained by least-squares

Table 1. Point positions for ScRh₃Si₇ and ScIr₃Si₇ (space group R3c, hexagonal axes)

Isotropic temperature factors are expressed as T =

 $\exp\left[-2\pi^2 10^{-2} U(2\sin\theta/\lambda)^2\right]$. E.s.d.'s are given in parentheses.

	x	У	Ζ	U (Ų)
ScRh ₃ Si ₇				
Sc in $6(b)$	0	0	0	0.69 (8)
Rh in 18(e)	0.3223 (2)	0	1	0.39 (3)
Si(1) in $36(f)$	0.5380 (5)	0.6786 (4)	0.0302 (2)	0.73 (6)
Si(2) in $G(a)$	0	0	4	0·8 (Ì)
ScIr ₃ Si ₇				
Sc in $6(b)$	0	0	0	1.2 (3)
Ir in 18(e)	0.3234 (3)	0	ł	0.45 (5)
Si(1) in $36(f)$	0.539(1)	0.680(1)	0.029 (1)	0·9 (1)
Si(2) in $6(a)$	0	0	1	1.1 (4)

Table 2. Interatomic distances d (Å) and rounded values $\Delta (\equiv d - \sum r)$ (Å) for ScRh₃Si₇ and ScIr₃Si₇ up to 1.3 $\sum r$

The atomic radii (r) used for Sc, Si, Rh and Ir are 1.62, 1.32, 1.34 and 1.36 Å respectively. E.s.d.'s are given in parentheses.

ScRh ₃ Si ₇	d	⊿	ScIr ₃ Si ₇	d	⊿
Sc -6Rh	3.027 (1)	+0·07	Sc -6Ir	3.033 (2)	+0.05
-6Si(1)	3.075 (3)	+0·14	-6Si(1)	3.12 (1)	+0.18
-6Si(1)	3.135 (4)	+0·20	-6Si(1)	3.12 (1)	+0.18
Rh -2Si(1)	2.417 (4)	-0·24	Ir -2Si(1)	2.41 (1)	-0.27
-1Si(2)	2.419 (1)	-0·24	-2Si(1)	2.42 (1)	-0.26
-2Si(1)	2.421 (3)	-0·24	-1Si(2)	2.426 (2)	-0.25
-2Si(1)	2.481 (3)	-0·18	-2Si(1)	2.507 (9)	-0.17
-2Sc	3.027 (1)	+0·07	-2Sc	3.033 (2)	+0.05
$\begin{array}{c} Si(1)-1Rh \\ -1Rh \\ -2Si(1) \\ -1Si(2) \\ -1Si(2) \\ -1Si(2) \\ -1Sic \\ -1Sc \\ -2Si(1) \\ -1Si(2) \end{array}$	2.417 (4) 2.421 (3) 2.481 (3) 2.587 (5) 2.679 (4) 2.688 (3) 2.720 (5) 3.075 (3) 3.135 (3) 3.300 (6) 3.353 (4)	$\begin{array}{c} -0.24 \\ -0.24 \\ -0.18 \\ -0.05 \\ +0.04 \\ +0.05 \\ +0.14 \\ +0.20 \\ +0.66 \\ +0.71 \end{array}$	Si(1)-1Ir -1Ir -2Si(1) -1Si(2) -1Si(1) -1Si(1) -1Si(1) -1Si -1Si -2Si(1) -1Si(2)	2.41 (1) 2.42 (1) 2.507 (9) 2.59 (2) 2.72 (1) 2.72 (1) 3.12 (1) 3.12 (1) 3.28 (2) 3.37 (1)	$\begin{array}{c} -0.27 \\ -0.26 \\ -0.17 \\ -0.05 \\ +0.05 \\ +0.08 \\ +0.08 \\ +0.18 \\ +0.18 \\ +0.64 \\ +0.73 \end{array}$
Si(2)-3Rh	2·419 (1)	0·24	Si(2)-3Ir	2-426 (2)	-0·25
-6Si(1)	2·688 (3)	+0·05	-6Si(1)	2-69 (1)	+0·05
-6Si(1)	3·353 (4)	+0·71	-6Si(1)	3-37 (1)	+0·73

refinement of the 2θ values of 50 reflections. According to the Laue class (3m) and the conditions limiting possible reflections (*hkil*: -h + k + l = 3n; *hh*0*l*: l =2n) the possible space groups are R3c or R3c. Data collections for ScRh₃Si₇ and ScIr₃Si₇ were carried out on a four-circle diffractometer (Philips PW 1100) in the $\omega - 2\theta$ mode with graphite-monochromated Mo Ka radiation, out to a limit of sin $\theta/\lambda = 0.7 \text{ Å}^{-1}$, yielding 314 (305) independent reflections. The structure was solved from a Patterson map with the Rh data set. A difference synthesis led us to introduce an extra Si atom, resulting in the composition 1:3:7. Scale factors, positional parameters and isotropic parameters refined satisfactorily in R3c for the two compounds with the full-matrix least-squares program CRYLSO (XRAY system, 1976). Scattering factors were taken from International Tables for X-ray Crystallography (1974) and intensities were corrected in both cases for spherical absorption. Refinements for nine structural parameters were obtained from 272 (250) reflections with $|F_o| > 3\sigma(F_o)$. $R = \sum |\Delta F| / \sum |F_o| = 0.037$ for ScRh₃Si₇ after correction of the structure factors for isotropic secondary extinction and 0.072 for ScIr₃Si₇ (without extinction correction).* Atomic parameters are given in Table 1 and interatomic distances in Table 2.

Discussion. A convenient way to describe the crystal structure of $ScRh_3Si_7$ is to concentrate at first only on the Rh and Sc arrangement. The Rh atoms alone form a hexagonal close-packed (h.c.p.) arrangement with six layers per unit cell stacked along c. Each Rh double

* Lists of structure factors for ScRh₃Si, and ScIr₃Si, have been deposited with the British Library Lending Division as Supplementary Publication No. SUP 35830 (5 pp.). Copies may be obtained through The Executive Secretary, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England.



Fig. 1. Projection of Rh and Sc sites along [0001]. The Rh atoms are hexagonal close-packed (stacking positions A and B) while the Sc atoms occupy one third of the available octahedral interstices (stacking positions γ' , γ'' , γ'''). If we assume the Rh A layer to be at height $-\frac{1}{12}$ and the Rh B layer to be at $+\frac{1}{12}$, the Sc atoms occupy site γ' at height 0. The stacking of the Rh and Sc atoms in the complete structure can be described by the sequence $A\gamma' B\gamma'' A\gamma''' B\gamma''$ where the distance between neighbouring levels corresponding to neighbouring letters is $\frac{1}{24}$ of the c translation.



Fig. 2. Arrangement of the Sc-centred Rh octahedra (heavy lines) and the Si double tetrahedra (thin lines) centred on (1120) in ScRh₃Si₇. Only the Sc atoms (small circles) and the Si(2) atoms at the middle of the double tetrahedra are exactly on (1120). Only the front faces of the polyhedra are shown. Octahedra and double tetrahedra appear in two different positions which differ by a rotation of 180° around [0001].

layer may be described as a sheet of edge-connected Rh octahedra and one out of three of these octahedral sites is occupied by a Sc atom. Fig. 1 shows that the distribution of the Sc atoms on the available octahedral sites in the h.c.p. arrangement of Rh atoms can be expressed by the sequence $A\gamma'B\gamma''A\gamma'''B\gamma'A\gamma''B\gamma'''$. Roman letters refer to the Rh positions and Greek letters to Sc positions, the primes being used to differentiate between the three possible octahedral interstitial sites per AB double layer. A binary structure corresponding to the ScRh₃ arrangement in ScRh₃Si₇ is already known for PdF₃ (Hepworth, Jack, Peacock & Westland, 1957). The ideal c/a ratio for the PdF₃ type is $2\sqrt{2} = 2.818$. However, for ScRh₃Si₇, owing to the presence of the Si atoms, we find 2.62.

Si atoms centre one out of two of the triangular faces of the empty Rh octahedra. Two of these octahedra share a common face which is centred by a Si(2) atom. The Si atom grouping can be conveniently represented as double tetrahedra having one apex in common. Only Si(2) is common to both tetrahedra, the remaining six atoms being Si(1). The arrangement of Sc-centred Rh octahedra and Si double tetrahedra in the (1120) plane is shown in Fig. 2. The Rh atom itself is surrounded by a more complicated coordination polyhedron consisting of two Sc and seven Si atoms. The geometrical arrangement of the seven Si around the Rh atoms is similar to the Si surrounding of Rh in RhSi with the FeSi structure type (Engström & Johnsson, 1965).

The ScRh₃Si₇-type structure seems to be dominated by the short Rh-Si distances (Table 2). These contractions in the distances of nearly 0.25 Å with respect to the sum of the metallic radii are not unusual. A similar shortening of bonds has been reported, for example, by Engström (1970) in binary platinum silicides. On the other hand, no such interactions exist between Sc and Si atoms. In the binary transition-metal (T) silicides the T-Si contractions (Aronsson, 1966) become generally more pronounced the higher the group number of the T partner. This rule, which is effectively valid for the ScRh₃Si₇-type structure, is no longer true for other ternary compounds such as Sc₅Co₄Si₁₀ (Braun, Yvon & Braun, 1980) or ScRhSi₂ (Chabot, Braun, Yvon & Parthé, 1981). In both these cases strong interactions exist between Si and Sc as well as between Si and the other T elements.

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